## ReSecu\_4\_A<sub>M</sub>BRAM<sup>s</sup>

## TOWARDS INCREASED RELIABILITY AND HARDWARE SECURITY ON MODERN NANOSCALE FPGAS

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Motivation – Wide portfolio of new technologies in design and manufacturing of advanced integrated circuits enables higher integration of complex structures at ultra-high nanoscale densities, but also sensitivity to various changes of the internal nanostructures and their parameters, resulting in the requirement of advanced measurements and complex reliability assessments.

The principle and utilization of BRAMS

Controller

LOCAT RING (e.g. 4 stages)

BRAM

Locations of BRAMS

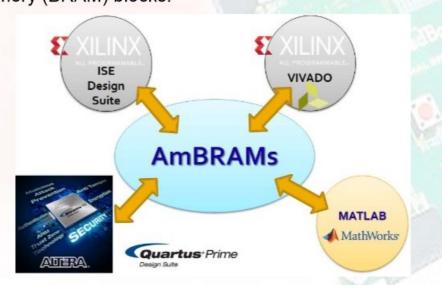
To #1/µCore

LING RING [e.g. 15 stages]

RING RING (e.g. 4 stages)

RING RING

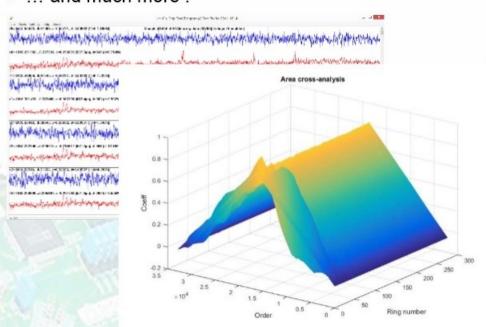
AmBRAM<sup>s</sup> is new method and developed advanced Analysis Tool and Framework for Advanced Measurements and Reliability Assessments on Modern Nanoscale FPGAs creates revolutionary new set of tools enables complex labon-chip solutions in nanoscale FPGAs. The key method is based on the basic principle of on-chip parameter measurements utilizing programmable structures. Available FPGA blocks are configured into multiple oscillators across the chip and the resulting data streams are sampled in the synchronous memory blocks as a new way of using block memory (BRAM) blocks.



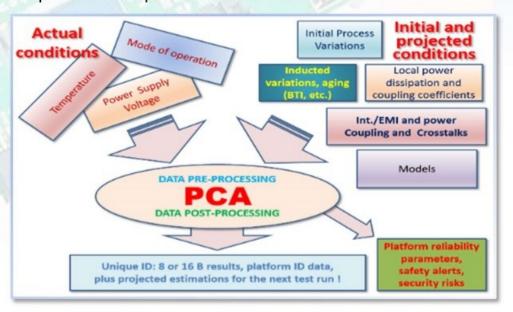
**A**<sub>m</sub>**BRAM**<sup>s</sup> has been enhanced of advanced measurements and data processing supporting platform identification and security support functionality including tampering detection preferably in modern nanoscale programmable devices.

**ReSecu**4**A**<sub>m</sub>**BRAM**<sup>s</sup> is a set of tools and methods based on A<sub>m</sub>BRAM<sup>s</sup> lab-on-chip platform and focused on safety and security of modern systems.

- ✓ Internal parameter measurements in FPGAs
- ✓ Device and platform identification
- ✓ Identification of crosstalk path and mutual impacts
- ✓ Identification of changes in internal parameters
- ✓ Parameter-aware placement
- ✓ ... and much more!



It will be presented on VLIW soft processor cores equipped with a security IP, and also showing POF solutions and related functionality. Detection of power voltage variation using AmBRAMs technology is incorporated in the processor application and demonstrating it on a complex processor system. Presented on 28nm LP or 20nm HP UltraScale Xilinx FPGA devices. Widely used 28nm FPGA solution will also show simple HW adjustments enabling support of power supply change required the demonstrator and for adaptive control presented as well.



Available for FPGAs from 90 nm down to 20 nm technologies.

## References

- [1] PFEIFER, P., KACZER, B., PLIVA, Z.: A Reliability Lab-on-chip Using Programmable Arrays, 52nd IEEE International Reliability Physics Symposium, Hawaii, USA, 2014, DOI: 10.1109/IRPS.2014.6861123
- [2] PFEIFER, P.: Towards Increased Reliability and Hardware Security using Advanced Measurements and Data Processing on Modern Nanoscale FPGAs, Joint MEDIAN&TRUDEVICE Open Forum, 30 September 2014, Amsterdam, The Netherlands